Europass Curriculum Vitae

PERSONAL INFORMATION

First name / Surname	**DR. GHEORGHE BORODI**
Adress	Str Donat 67-103, 400293 Cluj-Napoca, Romania
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Nationality	Romana
Date of bird	August, 24, 1949

WORK EXPERIENCE

Perioad	1973-present
Name and address of employer	National Institute for Research and Development of Isotopic and Molecular Technologies, INCDTIM, 67-103 Donat Str., RO-400293 Cluj-Napoca 5, Romania
Main activities and responsabilities	Research and Development. Basic and applied research
Occupation or position held	Physicist, Scientific Researcher I.
Main activities and responsibilities	Scientific researcher with extensive experience in: X-ray powder diffraction, X-ray single crystal diffraction, Small Angle X-ray scattering, Thin films X-ray diffraction.
Perioad	1972-1973
Name and address of employer	Research Center for Electronic Components Baneasa-Bukharest Romania
Occupation or position held	Physicist
Main activities and responsibilities	Planar technology of semiconductor devices
Perioad	2004 (6 months)
Name and address of employer	University of Amsterdam (UVA)
Main activities and responsabilities	Basic and applied research
Occupation or position held	NATO scholarship
Main activities and responsabilities	Crystal structure determination:Cyclodextrin inclusion complexes from X-Ray powder diffraction data.

EDUCATION AND TRAINING

Period	1992-1998
Name of organisation	Babeş-Bolyai University, Faculty of Physics Cluj-Napoca, Romania
Principal subjects	Structural characterization by X-ray diffraction of oxidic and calcogenide compounds.
Title of qualification awarded	Diploma Ph. D. (Summa Cum Laude)
Period	1967-1972
Name of organisation	Babeş-Bolyai University, Faculty of Physics Cluj-Napoca, Romania
Title of qualification awarded	B.Sc. in Physics, (Solid state Physics), B.Sc. Diploma

PERSONAL SKILLS

MOTHER TONGUE	**ROMANIAN**
LIMBI STRAINE	**ENGLISH,** Very good

PROFFESSIONAL SKILLS

Small angle X-ray scattering: determination of: specific surfaces, pore sizes and pore sizes distribution; Calculation of energy bands in solid; Structural characterization of amorphous materials using x-ray Scattering; X-ray powder diffraction: qualitative and quantitative phase analysis, microstructural analysis (crystallite size and strain), degree of crystalinity evaluation; Thin film X-ray diffraction:reflectivity, reciprocal space map, pole figure,rocking curve etc; Ab initio crystal structure determinatin from powder diffraction data: powdre diffraction indexing, obtaining of structural model, Riedveld refinement; Crystal structure determination from single crystal; The difraction methods methods have been applied to the following types of materials: semiconductors, superconductors, perowkites, oxidic materials, catalysts, metallic compounds, graphenes, magnetic materials, pharmaceutical compounds, inclusion complexes, MOFs

Other mentions

Teaching activities: Course of diffractometric methods, Seminar and Laboratory of Solid state Physics, 175 ISI Papers, 1240 Citations without auto citations, Hirsh Index:19

26 06 2019 Dr. Gheorghe Borodi